

MOSFET

600V CoolMOS™ C7 Power Transistor

CoolMOS™ C7 is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies.

600V CoolMOS™ C7 series combines the experience of the leading SJ MOSFET supplier with high class innovation.

The 600V C7 is the first technology ever with R_{DS(on)}*A below 10hm*mm².

Features

- Suitable for hard and soft switching (PFC and high performance LLC)
- Increased MOSFET dv/dt ruggedness to 120V/ns
- Increased efficiency due to best in class FOM R_{DS(on)}*E_{oss} and R_{DS(on)}*Q_g
- Best in class R_{DS(on)} /package
- Qualified for industrial grade applications according to JEDEC (J-STD20 and JESD22)

Benefits

- Increased economies of scale by use in PFC and PWM topologies in the application
- Higher dv/dt limit enables faster switching leading to higher efficiency
- Enabling higher system efficiency by lower switching losses
- Increased power density solutions due to smaller packages
- Suitable for applications such as server, telecom and solar
- Higher switching frequencies possible without loss in efficiency due to low Eoss and Qg

Applications

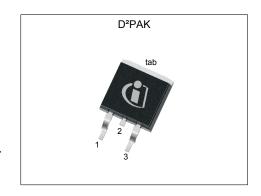
PFC stages and PWM stages (TTF, LLC) for high power/performance SMPS e.g. Computing, Server, Telecom, UPS and Solar.

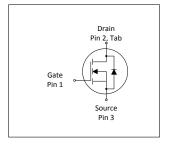
Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.



| Parameter | Value | Unit |
|---|-------|------|
| V _{DS} @ T _{j,max} | 650 | V |
| R _{DS(on),max} | 180 | mΩ |
| Q _{g.typ} | 24 | nC |
| I _{D,pulse} | 45 | A |
| I _{D,continuous} @ T _j <150°C | 22 | A |
| E _{oss} @400V | 2.7 | μJ |
| Body diode di/dt | 350 | A/µs |

| Type / Ordering Code | Package | Marking | Related Links |
|----------------------|-----------|---------|----------------|
| IPB60R180C7 | PG-TO 263 | 60C7180 | see Appendix A |











600V CoolMOS™ C7 Power TransistorIPB60R180C7



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1 Maximum ratings at $T_j = 25$ °C, unless otherwise specified

Table 2 Maximum ratings

| Davamatan | Ob. a.l | | Value | s | 11 | Note / Took Condition | |
|--|----------------------|------|-------|---------|------|---|--|
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition | |
| Continuous drain current ¹⁾ | I _D | - | - | 13 8 | А | T _C =25°C T _C =100°C | |
| Pulsed drain current ²⁾ | I _{D,pulse} | - | - | 45 | Α | T _C =25°C | |
| Avalanche energy, single pulse | E AS | - | - | 53 | mJ | I _D =3.3A; V _{DD} =50V; see table 10 | |
| Avalanche energy, repetitive | E AR | - | - | 0.26 | mJ | I _D =3.3A; V _{DD} =50V; see table 10 | |
| Avalanche current, single pulse | I _{AS} | - | - | 3.3 | Α | - | |
| MOSFET dv/dt ruggedness | dv/dt | - | - | 120 | V/ns | V _{DS} =0400V | |
| Gate source voltage (static) | V _{GS} | -20 | - | 20 | V | static; | |
| Gate source voltage (dynamic) | V _{GS} | -30 | - | 30 | V | AC (f>1 Hz) | |
| Power dissipation | P _{tot} | - | - | 68 | W | <i>T</i> _C =25°C | |
| Storage temperature | T _{stg} | -55 | - | 150 | °C | - | |
| Operating junction temperature | T _j | -55 | - | 150 | °C | - | |
| Mounting torque | - | - | - | n.a. | Ncm | - | |
| Continuous diode forward current | Is | - | - | 13 | Α | <i>T</i> _C =25°C | |
| Diode pulse current ²⁾ | I _{S,pulse} | - | - | 45 | Α | <i>T</i> _C =25°C | |
| Reverse diode dv/dt ³⁾ | dv/dt | - | - | 20 | V/ns | $V_{\rm DS}$ =0400V, $I_{\rm SD}$ <=5.2A, $T_{\rm j}$ =25°C see table 8 | |
| Maximum diode commutation speed | di _f /dt | - | - | 350 | A/μs | $V_{\rm DS}$ =0400V, $I_{\rm SD}$ <=5.2A, $T_{\rm j}$ =25°C see table 8 | |
| Insulation withstand voltage | V _{ISO} | - | - | n.a. | V | V _{rms} , T _C =25°C, t=1min | |

 $^{^{1)}}$ Limited by $T_{j\,\text{max}}.$ $^{2)}$ Pulse width t_p limited by $T_{j,\text{max}}$ $^{3)}$ Identical low side and high side switch

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2 Thermal characteristics

Table 3 Thermal characteristics

| Parameter. | Values | | | | | |
|---|-------------------|------|------|-------|------|---|
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition |
| Thermal resistance, junction - case | R _{thJC} | - | - | 1.832 | °C/W | - |
| Thermal resistance, junction - ambient | R _{thJA} | - | - | 62 | °C/W | device on PCB, minimal footprint |
| Thermal resistance, junction - ambient for SMD version | R_{thJA} | - | 35 | 45 | °C/W | Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thickness) copper area for drain connection and cooling. PCB is vertical without air stream cooling. |
| Soldering temperature, wave- & reflow soldering allowed | T _{sold} | - | - | 260 | °C | reflow MSL1 |

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3 Electrical characteristics

at T_j=25°C, unless otherwise specified

Table 4 Static characteristics

| Parameter | Oh o.l | Values | | | 11 | Nata / Tank Oam distant |
|----------------------------------|-----------------------|--------|----------------|-------|------|---|
| | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition |
| Drain-source breakdown voltage | V _{(BR)DSS} | 600 | - | - | V | V_{GS} =0V, I_D =1mA |
| Gate threshold voltage | V _{(GS)th} | 3 | 3.5 | 4 | V | $V_{\rm DS}=V_{\rm GS},\ I_{\rm D}=0.26{\rm mA}$ |
| Zero gate voltage drain current | I _{DSS} | - | - 10 | 1 - | μΑ | V _{DS} =600, V _{GS} =0V, T _j =25°C V _{DS} =600, V _{GS} =0V, T _j =150°C |
| Gate-source leakage current | I _{GSS} | - | - | 100 | nA | V _{GS} =20V, V _{DS} =0V |
| Drain-source on-state resistance | R _{DS(on)} | - | 0.155 0.346 | 0.180 | Ω | V _{GS} =10V, I _D =5.3A, T _j =25°C V _{GS} =10V, I _D =5.3A, T _j =150°C |
| Gate resistance | R _G | - | 0.85 | - | Ω | f=1MHz, open drain |

Table 5 Dynamic characteristics

| Demonstra | Or week all | | Values | | | |
|--|--------------------|------|--------|------|------|--|
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition |
| Input capacitance | Ciss | - | 1080 | - | pF | V _{GS} =0V, V _{DS} =400V, f=250kHz |
| Output capacitance | Coss | - | 18 | - | pF | V _{GS} =0V, V _{DS} =400V, f=250kHz |
| Effective output capacitance, energy related ¹⁾ | C _{o(er)} | - | 34 | - | pF | V _{GS} =0V, V _{DS} =0400V |
| Effective output capacitance, time related ²⁾ | C _{o(tr)} | - | 349 | - | pF | I _D =constant, V _{GS} =0V, V _{DS} =0400V |
| Turn-on delay time | t _{d(on)} | - | 9.3 | - | ns | $V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =5.3A, $R_{\rm G}$ =10 Ω ; see table 9 |
| Rise time | t _r | - | 7 | - | ns | $V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =5.3A, $R_{\rm G}$ =10 Ω ; see table 9 |
| Turn-off delay time | $t_{ m d(off)}$ | - | 50 | - | ns | $V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =5.3A, $R_{\rm G}$ =10 Ω ; see table 9 |
| Fall time | t _f | - | 6 | - | ns | $V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =5.3A, $R_{\rm G}$ =10 Ω ; see table 9 |

Table 6 Gate charge characteristics

| Parameter | Comple of | | Values | | | Nata / Tant Candition |
|-----------------------|----------------------|------|--------|------|------|---|
| | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition |
| Gate to source charge | Q_{gs} | - | 5 | - | nC | $V_{\rm DD}$ =400V, $I_{\rm D}$ =5.3A, $V_{\rm GS}$ =0 to 10V |
| Gate to drain charge | Q_{gd} | - | 8 | - | nC | $V_{\rm DD}$ =400V, $I_{\rm D}$ =5.3A, $V_{\rm GS}$ =0 to 10V |
| Gate charge total | Qg | - | 24 | - | nC | $V_{\rm DD}$ =400V, $I_{\rm D}$ =5.3A, $V_{\rm GS}$ =0 to 10V |
| Gate plateau voltage | V _{plateau} | - | 5.0 | - | V | $V_{\rm DD}$ =400V, $I_{\rm D}$ =5.3A, $V_{\rm GS}$ =0 to 10V |

 $^{^{1)}}$ $C_{\text{o(er)}}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V $^{2)}$ $C_{\text{o(tr)}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

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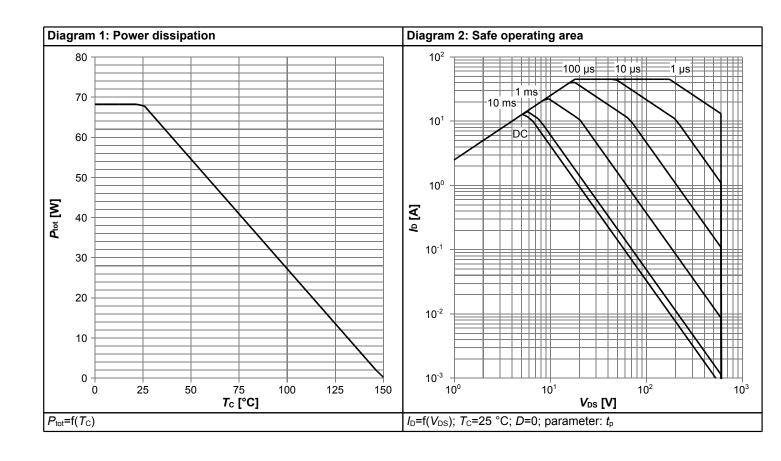


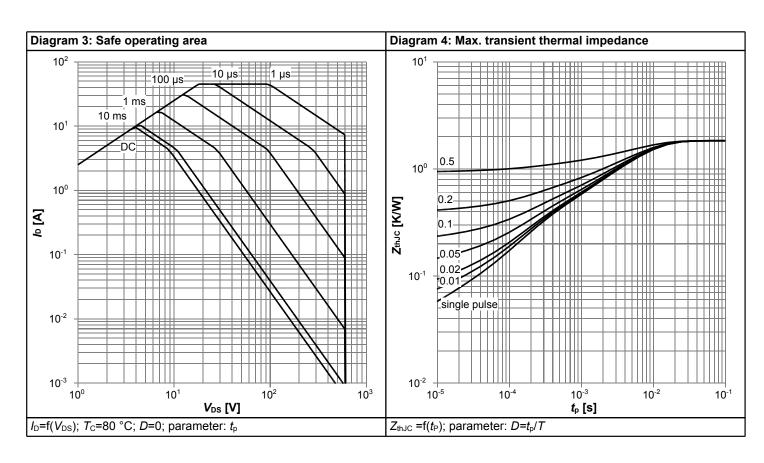
Table 7 Reverse diode characteristics

| Parameter | Cumbal | Values | | | 11 | Nata / Tant Candition |
|-------------------------------|------------------------|--------|------|------|------|---|
| | Symbol | Min. | Тур. | Max. | Unit | Note / Test Condition |
| Diode forward voltage | V _{SD} | - | 0.9 | - | V | V _{GS} =0V, I _F =5.3A, T _j =25°C |
| Reverse recovery time | t _{rr} | - | 280 | - | ns | V_R =400V, I_F =5.3A, di_F/dt =100A/ μ s; see table 8 |
| Reverse recovery charge | Qrr | - | 2.6 | - | μC | V_R =400V, I_F =5.3A, di_F/dt =100A/ μ s; see table 8 |
| Peak reverse recovery current | I _{rrm} | _ | 21 | - | А | V_R =400V, I_F =5.3A, di_F/dt =100A/ μ s; see table 8 |

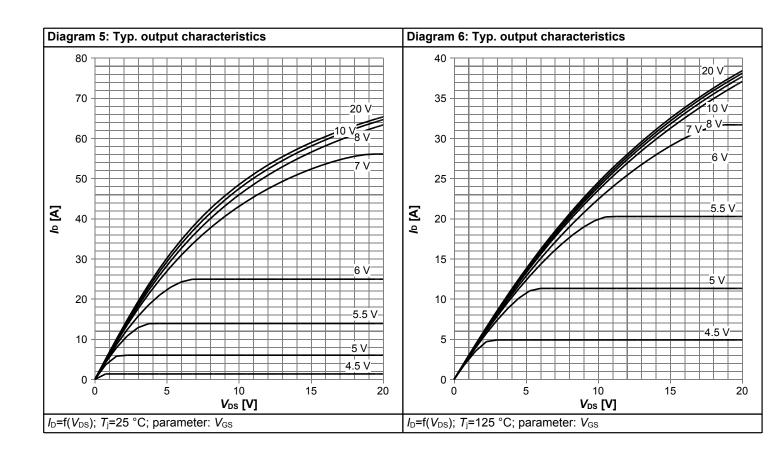


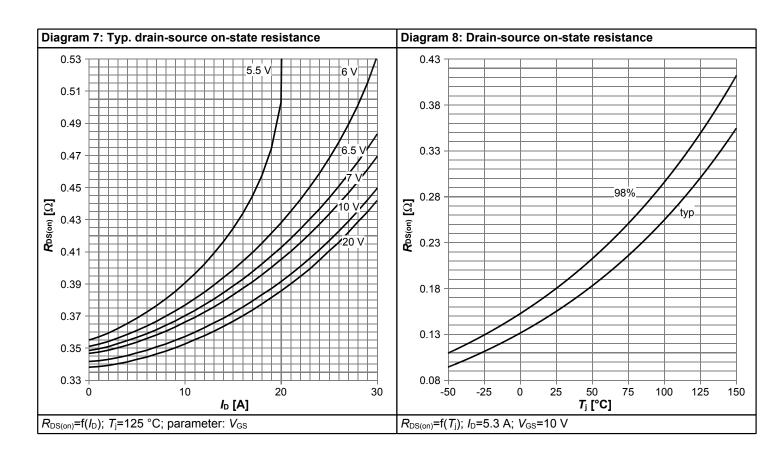
4 Electrical characteristics diagrams



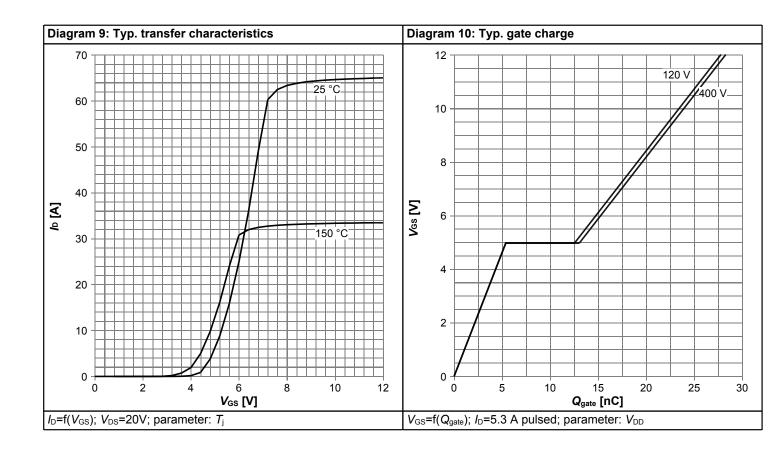


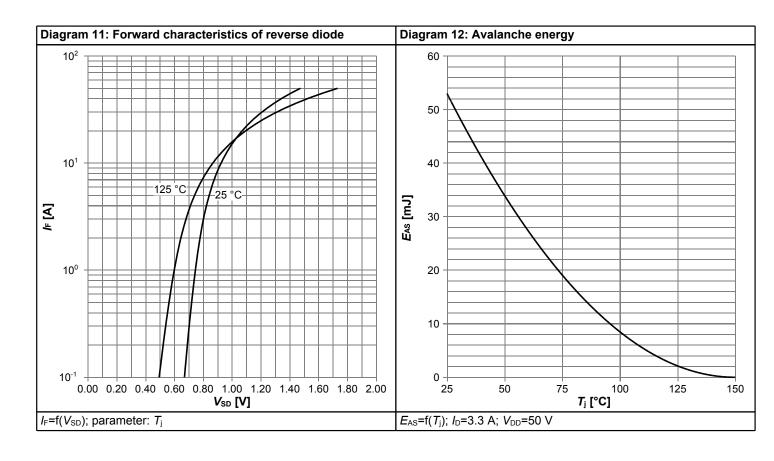




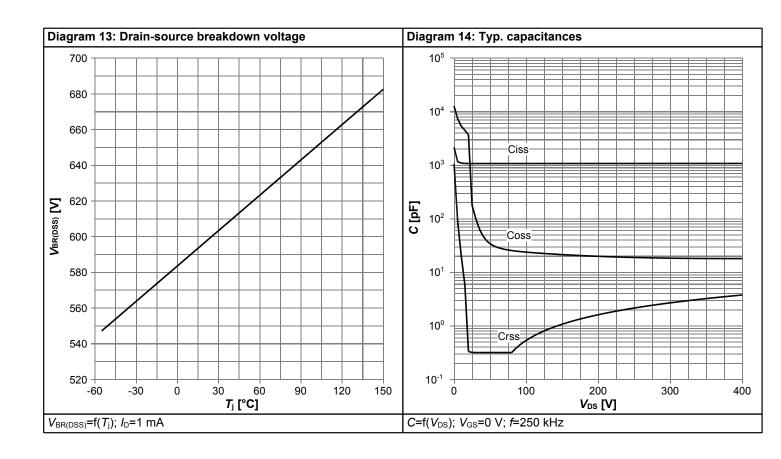


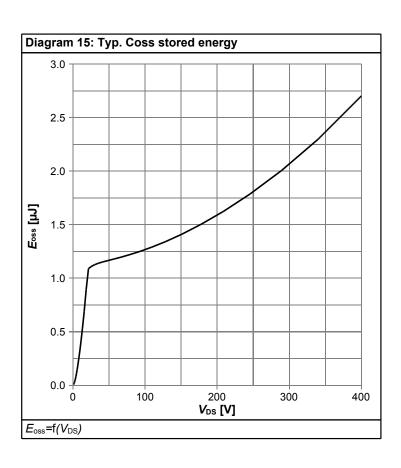














5 Test Circuits

Table 8 Diode characteristics

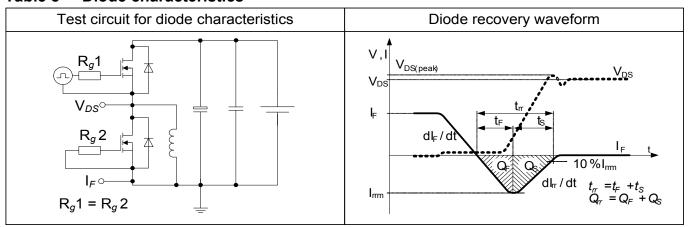


Table 9 Switching times

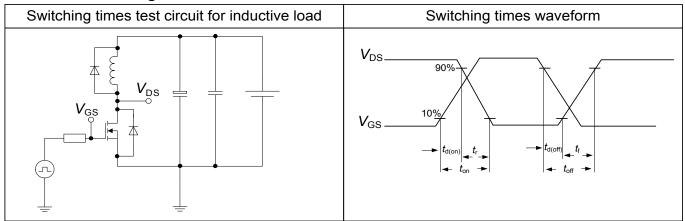
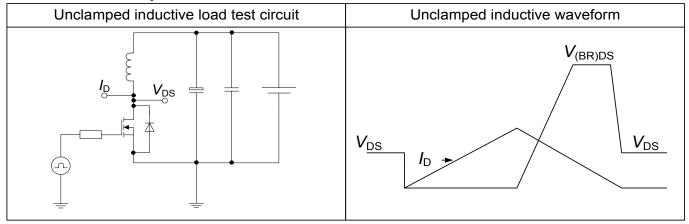


Table 10 Unclamped inductive load





6 Package Outlines

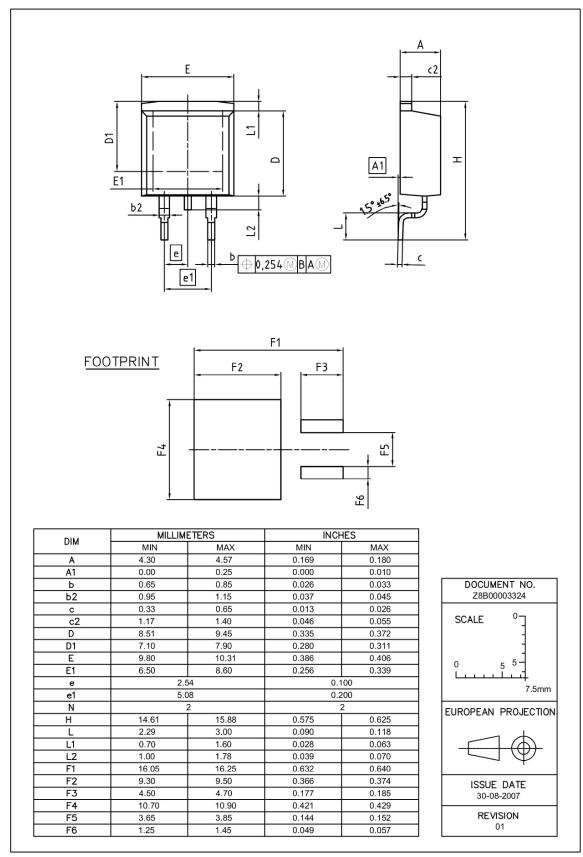


Figure 1 Outline PG-TO 263, dimensions in mm/inches

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7 Appendix A

Table 11 Related Links

• IFX CoolMOS™ C7 Webpage: www.infineon.com

• IFX CoolMOS[™] C7 application note: <u>www.infineon.com</u>

• IFX CoolMOS™ C7 simulation model: www.infineon.com

• IFX Design tools: www.infineon.com

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Revision History

IPB60R180C7

Revision: 2016-03-01, Rev. 2.0

Previous Revision

| Revision | Date | Subjects (major changes since last revision) | | | | |
|----------|------------|--|--|--|--|--|
| 2.0 | 2016-03-01 | Release of final version | | | | |

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Final Data Sheet 14 Rev. 2.0, 2016-03-01